# Voronoi Diagrams in $L_\infty$ - for VLSI Critical Area Computation Sandeep Kumar Dey and Evanthia Papadopoulou

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# Voronoi Diagrams are important in VLSI CAD

There are different variants of Voronoi Diagram such as nearest-neighbor, higher order and the farthest-neighbor which fits in naturally in different practical situations of a VLSI layout.

- The critical Area extraction for shorts in a VLSI layout can be computed as a function of the second order  $L_{\infty}$  Voronoi diagram.
- The critical area for opens can be modeled using higher order Voronoi diagrams.
- The problem of computing critical area for via-blocks reduces to computing a Hausdorff Voronoi digram of polygons representing clusters of redundant vias.

# $2^{nd}$ order subdivision with in a Voronoi cell



#### **Critical Area for Shorts**

The extraction of critical area is a fundamental problem in VLSI yield prediction.

# Why and When $L_{\infty}$ ?

- Parabolic arcs in Euclidean Voronoi diagram make its robust implementation harder.  $L_{\infty}$  Voronoi diagram contains only straight line segments.
- In applications where Euclidean accuracy is not needed,  $L_{\infty}$  can give a more practical and simple solution.

## $L_{\infty}$ Distance and Bisectors

• The  $L_{\infty}$  distance between the two geometric objects is the side length of the smallest isothetic square touching them.



- The *critical radius* of an arbitrary point *p* in the layout for shorts is the radius of the smallest defect which if centered at *p* overlaps with two different polygons.
- The critical radius of p is the distance of p from the second nearest polygon to p.
- Critical area within a second order Voronoi cell V is given by:  $A_c(V) = \int_0^\infty A(r, V)D(r)dr$ , which can be discretized as a summation  $(A_c = \sum_V A_c(V))$  of second order  $L_\infty$  Voronoi edges.



The decomposition of a second order Voronoi cell V into trapezoids

- The critical area within a rectangle R is  $A_c(R) = \frac{r_0^2 S}{2} (\frac{l}{r_i} \frac{l}{r_k})$
- The critical area within a red triangle  $T_{red}$  is given by  $A_c(T_{red}) = \frac{r_0^2 S}{2} (STln(\frac{r_k}{r_j}) - \frac{l}{r_k})$

The L-infinity bisector of two lines

The L-infinity bisector between a point and a line

## $L_{\infty}$ Voronoi Diagram of Polygons



Data-Structures required to construct and store the Voronoi diagram:

- A Priority Queue to store the events.
- A balanced binary tree to store the sweep line status.
- A half edge data-structure (DCEL) to store the planer subdivision.

# $L_{\infty}$ Farthest Segment Voronoi Drigram



• The critical area within a blue triangle is given by  $T_{blue}$  is  $A_c(T_{blue}) = \frac{r_0^2 S}{2} \left( \frac{l}{r_j} - STln(\frac{r_k}{r_j}) \right)$ 

*l* is the size of the edge of *R*,  $T_{red}$  and  $T_{blue}$  parallel to e.  $r_j$  and  $r_k$  minimum and maximum critical radius of their vertices.

• Given 2nd order Voronoi diagram of polygons on a layer in a VLSI circuit and assuming that the defects are square following the  $r_0^2/r^3$  defect density distribution, the critical area for shorts in that layer is given by

$A_c = r_0^2 \left(\sum_{\substack{red,\\nrime}}\right)$	$\frac{S_i l_i}{r_i} - \sum_{\substack{blue, \\ prime}}$	$\frac{S_i l_i}{r_i} + \frac{1}{2}$	$\sum_{\substack{red,\\ on nrime}} S_e^2 T_e$	$\frac{r_k}{r_j} - \frac{1}{2}$	$\sum_{\substack{blue,\\on prime}}$	$S_e^2 T_e ln \frac{r_k}{r_j}$ -	$\left  \frac{B}{2} \right $
preme	prince			100			
$e_i$	$e_i$		$e_j$ ,		$e_j$ ,		
			wrt		wrt		
			e		e		

#### Discussion

The  $L_{\infty}$  Voronoi diagram is a simple planar subdivision consisting of straight line segments and is perticularly useful in the VLSI CAD applications where proximity information is needed.

• Given the structure of neighborhood information the farthest segment voronoi diagram in  $L_{\infty}$  can be computed in linear time.

#### References

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